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LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT M. Toshiyuki, Y. Masami, H. Yoshihiro	
FILING DATE November 2, 2000		GROUP 2858 2829	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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SDA	AT	<i>Op-amp circuit measures diode-junction capacitance</i> , by D. Monticelli and T. Frederiksen. Engineer's notebook, Electronics, July 10, 1975
EXAMINER:	T.R. L.	CITE CONSIDERED: 5/22/02
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

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